



BSI Standards Publication

Particle size analysis — Laser diffraction methods

National foreword

This British Standard is the UK implementation of [ISO 13320:2020](#). It supersedes [BS ISO 13320:2009](#), which is withdrawn.

The UK participation in its preparation was entrusted to Technical Committee LBI/37, Particle characterization including sieving.

A list of organizations represented on this committee can be obtained on request to its committee manager.

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**Particle size analysis — Laser
diffraction methods**

Analyse granulométrique — Méthodes par diffraction laser



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Contents

	Page
Foreword	v
Introduction	vi
1 Scope	1
2 Normative references	1
3 Terms, definitions and symbols	1
3.1 Terms and definitions.....	1
3.2 Symbols.....	6
4 Principle	8
4.1 General.....	8
4.2 Theory.....	8
4.3 Typical instrument and optical arrangement.....	9
4.4 Measurement zone.....	11
4.5 Application and sample presentation.....	11
4.6 Off-line measurements.....	12
4.7 In-line measurements.....	12
4.8 Online measurements.....	12
4.9 At-line measurements.....	13
4.10 Scattering and detectors.....	13
5 Operational requirements and procedures	13
5.1 Instrument location.....	13
5.2 Dispersion gases.....	13
5.3 Dispersion liquids.....	14
5.4 Sample inspection, preparation, dispersion and concentration.....	14
5.4.1 Sample inspection.....	14
5.4.2 Preparation.....	14
5.4.3 Dispersion.....	14
5.4.4 Concentration.....	15
5.5 Measurement.....	15
5.5.1 Setting up instrument and blank measurement.....	15
5.5.2 Sample preparation.....	16
5.5.3 Data collection of the scattering pattern.....	16
5.5.4 Selection of an appropriate optical model.....	16
5.5.5 Conversion of scattering pattern into PSD.....	16
5.5.6 Robustness.....	17
5.6 Resolution and sensitivity.....	17
5.6.1 General.....	17
5.6.2 Resolution.....	17
5.6.3 Sensitivity and result variability.....	17
6 Accuracy repeatability and instrument qualification	18
6.1 General.....	18
6.2 Accuracy.....	19
6.2.1 Introduction.....	19
6.2.2 Accuracy test.....	19
6.3 Instrument repeatability.....	19
6.3.1 Introduction.....	19
6.3.2 Repeatability test.....	19
6.4 Method repeatability.....	20
6.4.1 Introduction.....	20
6.4.2 Method repeatability test.....	20
6.5 Accuracy under intermediate precision conditions.....	20
6.5.1 General.....	20
6.5.2 Intermediate precision conditions (general test).....	21

7	Reporting of results	21
7.1	General.....	21
7.2	Sample.....	21
7.3	Dispersion.....	22
7.4	Laser diffraction measurement.....	22
7.5	Analyst identification:.....	22
	Annex A (informative) Theoretical background of laser diffraction	24
	Annex B (informative) Advice on dispersion liquids	41
	Annex C (informative) Dispersion methods — Recommendations	42
	Annex D (informative) Instrument preparation — Recommendations	44
	Annex E (informative) Error sources and diagnosis	46
	Annex F (informative) Refractive index — Recommendations	49
	Annex G (informative) Laser diffraction robustness and ruggedness	51
	Annex H (normative) Certified reference materials, reference materials and comparison parameters	54
	Bibliography	57

Foreword

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This document was prepared by Technical Committee ISO/TC 24, *Particle characterization including sieving*, Subcommittee SC 4, *Particle characterization*.

This second edition cancels and replaces the first edition ([ISO 13320:2009](http://www.iso.org/iso/13320:2009)), which has been technically revised. The main changes compared to the previous edition are as follows:

- a) protocols for evaluation of accuracy and qualification of instrument were newly developed;
- b) new [Annex H](#) (normative) for usage of reference material has been added;
- c) new descriptions for wider applications, such as off-line, online, in-line and at-line have been added;
- d) some informative parts have been moved to new annexes;
- e) minor revisions and updates have been made throughout the document.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at www.iso.org/members.html.